

## TIME INVARIANT FEATURE LOCATION METHOD AND SYSTEM

## ABSTRACT OF THE INVENTION

One aspect of the invention is a method for improving the quality of image data. The method comprises the step of identifying a reference feature whose characteristics are invariant as the film develops. The method also comprises the step of adjusting image data in response to the reference feature, where the image data and the reference feature captured from the film while the film has developing chemical applied thereto.